

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

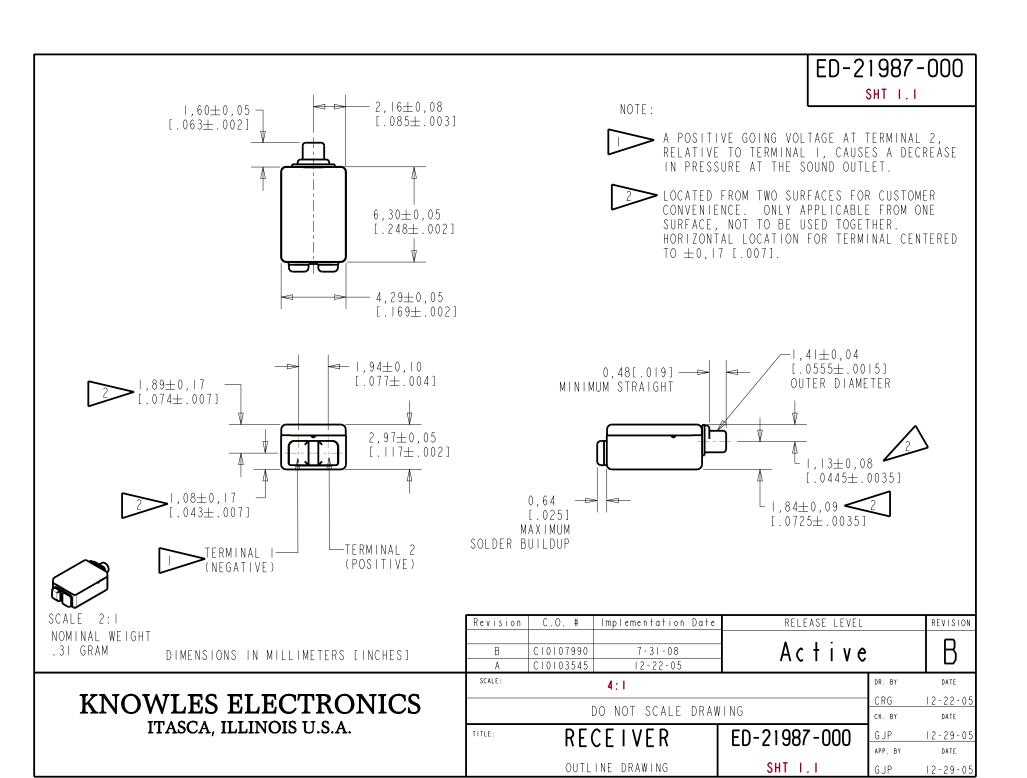
Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

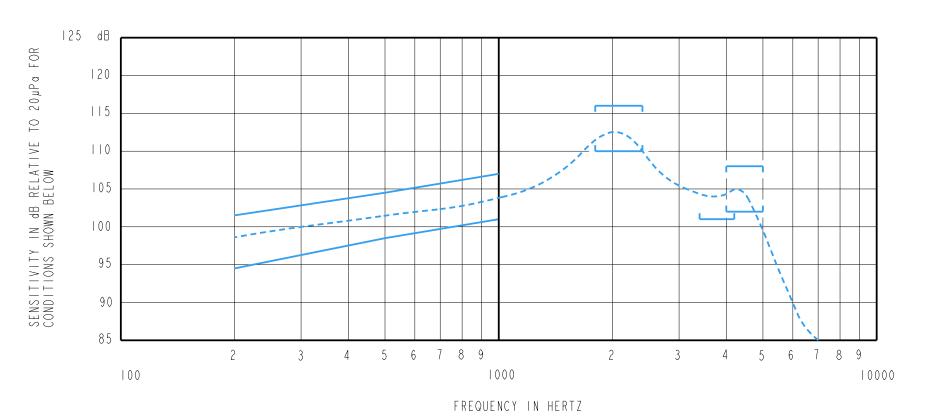








TYPE II DAMPING



NOTES:

I. MEASUREMENTS MADE USING 10mm (.394") X 1mm (.039") ID TUBE CONNECTED TO A SIMULATED ANSI \$3.7-1973 TYPE HA-3 COUPLER. (IEC 126).

2.		SENSITIVITY	
FR	EQUENCY	MIN.	MAX.
	200 500 1000	94.5 98.5 101.0	101.5
	00-2400	110.0	116.0
) 0 - 4200) 0 - 5000	0 . 0 0 2 . 0	108.0

- 3. RESPONSE, IMPEDANCE, AND DISTORTION MEASUREMENTS MADE USING THE ELECTRICAL TEST CONDITIONS SHOWN BELOW.
- 4. ELECTRICAL SOURCE IMPEDANCE MUST BE GREATER THAN 20 TIMES IKHZ IMPEDANCE FOR TEST CONDITIONS SHOWN BELOW.
- 5. INDIVIDUAL SPECIFICATIONS.

PORT LOCATION	IMPEDANCE OHMS ±15%		DCR @20°C	DISTORTION		ELECTRICAL TEST CONDITIONS	
	I K H z	500Hz	OHMS 土IO%	MAX. %	FREQ Hz	AC mA RMS	DC mA
12C	6300	3400	1493	5	800	0.25	0.35

Revision	C.O. #	Implementation Date	RELEASE LEVEL		REVISION
В	C10107990	7 - 31 - 08	Active		R
A	C10103545	12-22-05	ACTIVE		<u> </u>
WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR				DR. BY	DATE
		NT AND TEST METHOD VARIAT		CRG	12-22-05

KNOWLES ELECTRONICS ITASCA, ILLINOIS U.S.A.

			CN. BT	DATE
TITLE:	RECEIVER	ED-21987-000	GJP	12-29-05
			APP. BY	DATE
	PERFORMANCE SPECIFICATION	SHT 2.1	GJP	12-29-05